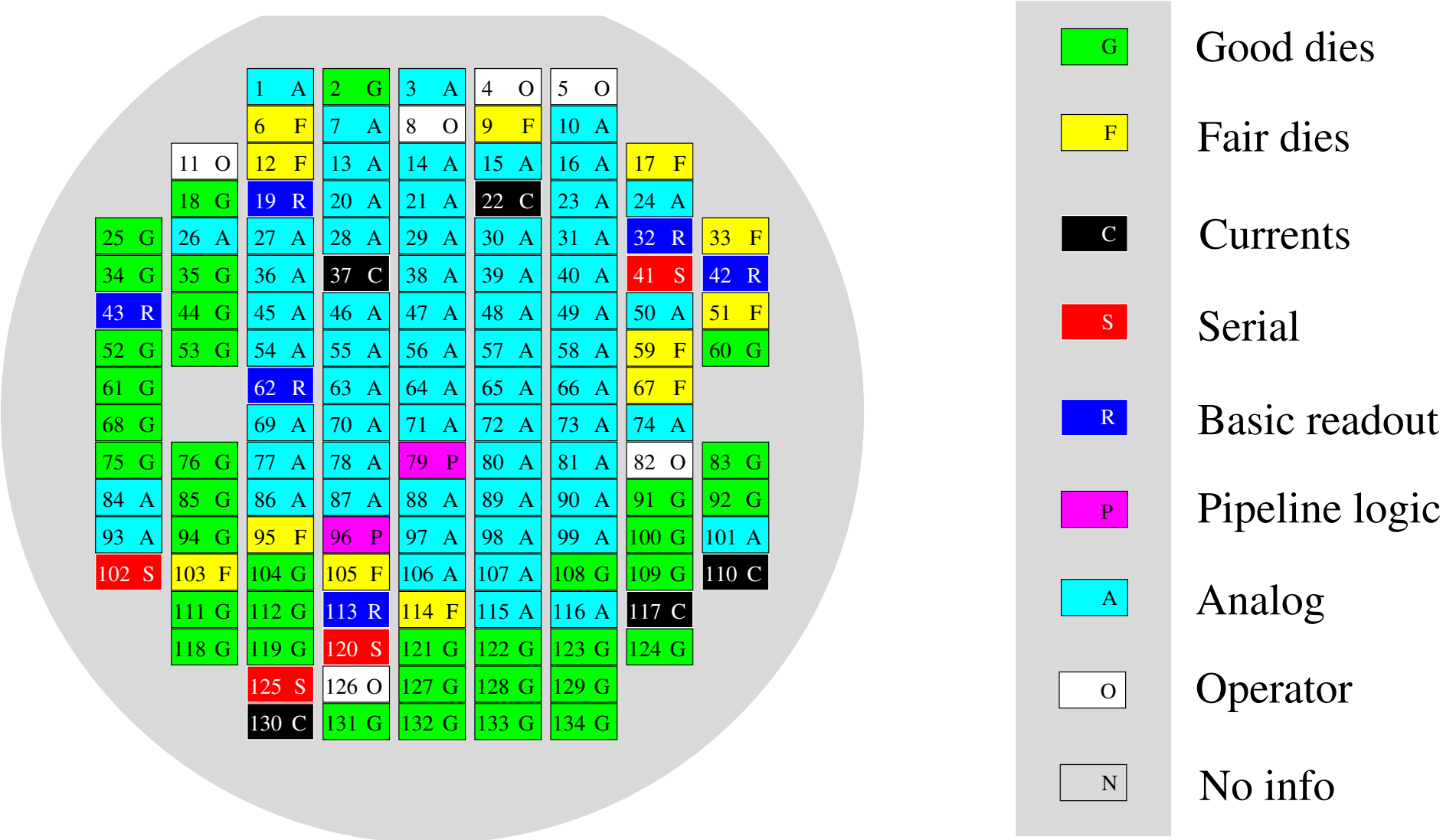
Types of die failures for wafer 167 s/n: Y21316-12-01

Date: 07/02/99